



XA-9387  
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Hitoshi TAKEUCHI

Appln. No.: 09/714,183

Group Art Unit: 2877

Filed: November 17, 2000

Examiner: R. Punnoose

For: ABERRATION MEASURING APPARATUS, ABERRATION MEASURING METHOD, PROJECTION EXPOSURE APPARATUS HAVING THE SAME MEASURING APPARATUS, DEVICE MANUFACTURING METHOD USING THE SAME MEASURING METHOD, AND EXPOSURE METHOD

\* \* \*

FOURTH SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Supplementing the Information Disclosure Statement

dated April 11, 2001, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

The Commissioner is hereby authorized to charge to Deposit Account No. 50-1165 any fees under 37 C.F.R. §§ 1.16 and 1.17 that may be required by this paper and to credit any overpayment to that Account. If any extension of time is required in connection with the filing of this

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paper and has not been requested separately, such extension  
is hereby requested.

Respectfully submitted,

MWS:jab

By:

  
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August 6, 2003

FORM PTO-1449

Atty. Docket No.

Appl. No.

XA-9387

09/714,183

## LIST OF DOCUMENTS CITED BY APPLICANT

Applicant

Hitoshi TAKEUCHI

Filing Date

November 17, 2000

Group

2877

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub-class	Filing Date
AA	3,973,953	8/10/76	Montgomery	96	1	
AB	4,405,232	9/20/83	Mansell	356	121	
AC	4,413,909	11/8/83	Pohle	356	354	
AD	4,438,330	3/20/84	Hardy	250	201	
AE	4,620,790	11/4/86	Hufnagel	356	124	
AF	4,667,103	5/19/87	Watson et al.	250	332	
AG	4,725,138	2/16/88	Wirth et al.	356	121	
AH	5,294,971	3/15/94	Braunecker et al.	356	121	
AI	5,300,766	4/5/94	Granger et al.	250	201.9	
AJ	6,052,180	4/18/00	Neal et al.	356	121	
AK	6,130,419	10/10/00	Neal	250	201.9	
AL	6,184,974	2/6/01	Neal et al.	356	121	

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Sub-class	Translation
AM						

OTHER (including author, title, date, pertinent pages, etc.)

AN	
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Examiner	Date Considered
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.